

Lecture 21: pn-junctions and diodes



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Lecture 21: pn-junction & diodes

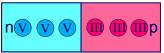
- formation of pn-junction
- solution of Poisson's equation for a pn-junction
- · built-in electric field and bias
- electrical operation under forward/reverse bias
- diode characteristics
- types of diodes: rectifiers, LEDs, Zener diodes, RTDs
- principle of bipolar junction transistors (BJTs)



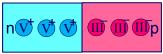
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Formation of pn-junction

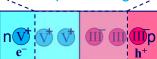
• contact two differently doped regions



 activate dopant atoms by annealing so they occupy lattice sites in tetrahedral coordination



 mobile charge carriers diffuse across boundary, recombine and form a thin depletion region



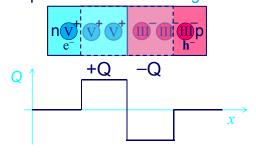


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Formation of pn-junction

ionised dopants create local charge density



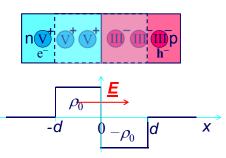
 within the depletion, there are no free carriers any more: the depletion region is intrinsic and does not conduct





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Poisson equation for pn-junction



consider step function of charge density:

$$\rho = \begin{cases} +\rho_0 \text{ for } -d < x < 0, \\ -\rho_0 \text{ for } 0 < x < d \end{cases}$$

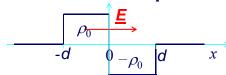
• solve Poisson equation $\nabla^2 V = \text{div grad V} = -\text{div } \underline{E} = -\rho/\epsilon$



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Poisson equation for pn-junction

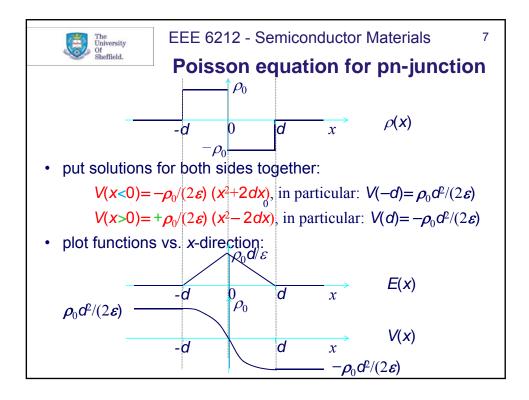


- solve Poisson equation in 1D (x-direction): $\partial^2 V/\partial x^2 = -\rho_0/\varepsilon$ for left (n) side
- double integration yields equation with 3 constants: $V(x)=c_1x^2+c_2x+c_3$
- then: $-E(x) = \partial V/\partial x = 2c_1x + c_2$ and $\partial^2 V/\partial x^2 = 2c_1 c_1 = -\rho_0/(2\varepsilon)$
- boundary condition: @ x=0: $V(0)=0 -> c_3=0$

@
$$x=-d$$
: $E(-d)=0 -> -2c_1(-d)-c_2=0$

 $-> c_2 = -\rho_0 d/\varepsilon$

->
$$V(x<0)=-\rho_0/(2\varepsilon) x^2 - \rho_0 d/\varepsilon x = -\rho_0/(2\varepsilon) (x^2+2dx)$$



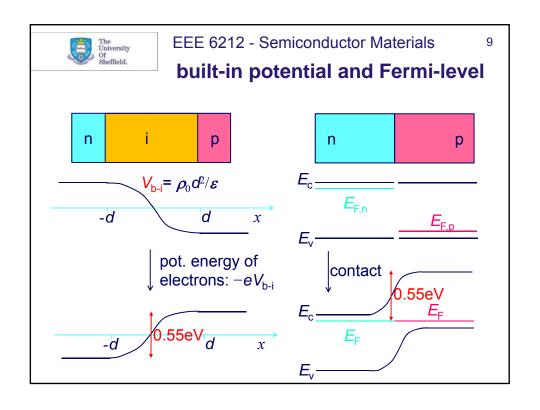


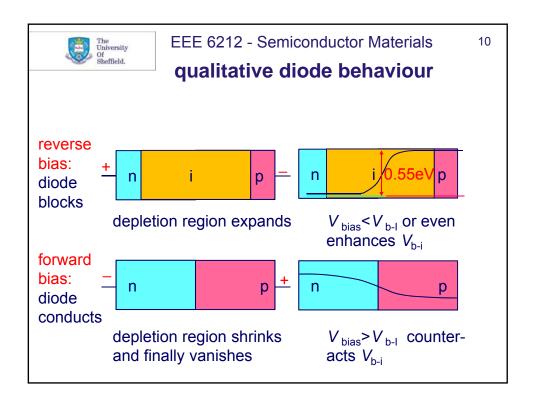
built-in potential and electric field

- · some typical numbers:
- Si, ε_r=11, doping of 1ppm, 2/3 of dopants activated, d=90nm
- $\rho_0 = 2/3 *10^{-6} *ne = 2/3 *10^{-6} *8/a^3 *e = 5335 \text{ C/m}^3$
- $\varepsilon = \varepsilon_0 \varepsilon_r = 8.8542 * 10^{-12} \text{ As/(Vm)} *11$
- $E_{\text{max}} = \rho_0 d/\varepsilon = 5.5 * 10^6 \text{ V/m}$
- $V_{b-i} = V(-d) V(d) = \rho_0 d^2 / \varepsilon = 0.55 \text{ V}$

This is the built-in potential across the pn-junction.

For the diode to conduct, the applied voltage (bias) needs to at least compensate this built-in potential.







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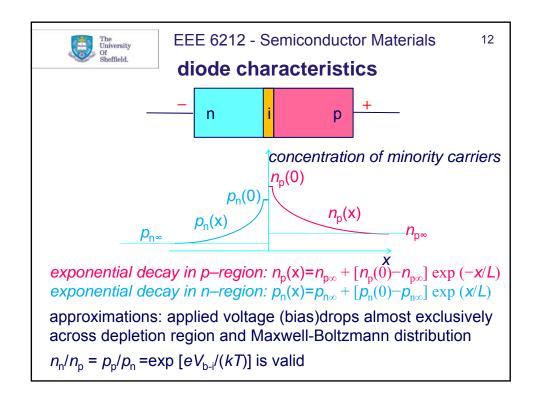
quantitative diode behaviour

- thermodynamic calculation of built-in potential: consider current densities due to both drift and diffusion on both sides:
 j_n=neμ_eE+eD_n ∂n(x)/∂x
 j_p=peμ_pE-eD_p ∂p(x)/∂x
- in equilibrium, there is no charge motion any more: $j_n = j_p = 0$ -> $E = -D_n/(n\mu_e) \partial n(x)/\partial x$ $E = D_n/(p\mu_n) \partial p(x)/\partial x$

->
$$V_{b-i} = -\int_{-d}^{d} E_{x} dx = -\int_{-d}^{d} -[D_{n}/(n\mu_{e}) \partial n(x)/\partial x] dx = D_{n}/\mu_{e} \int_{n_{p}}^{n_{n}} 1/n dn(x)$$

= $D_{n}/\mu_{e} \ln(n_{n}/n_{p})$
 $\approx kT/e \ln(N_{D}N_{A}/n_{i}^{2})$

For silicon with $N_{\rm A}$ = $N_{\rm D}$ =5*10¹⁵ cm⁻³, $n_{\rm i}$ = $p_{\rm i}$ \approx 10¹⁰ cm⁻³, room temp.: V_{b-i} \approx 0.026V ln (25*10¹⁰) \approx 0.68V





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diode characteristics

exponential decay in p-region: $n_p(x) = n_{p\infty} + [n_p(0) - n_{p\infty}] \exp(-x/L_n)$ exponential decay in n-region: $p_n(x) = p_{n\infty} + [p_n(0) - p_{n\infty}] \exp(x/L_p)$

approximations: applied voltage (bias)drops almost exclusively across depletion region and Maxwell-Boltzmann distribution

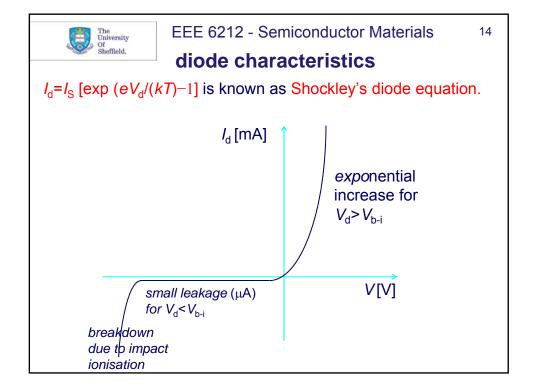
$$n_{\rm n}/n_{\rm p} = p_{\rm p}/p_{\rm n} = \exp\left[eV_{\rm b-i}/(kT)\right]$$
 is valid

- -> $n_{\rm p} = n_{\rm p} \exp\left[eV_{\rm b-i}/(kT)\right] \approx n_{\rm p}(0) \exp\left(-x/L\right) \exp\left[eV_{\rm b-i}/(kT)\right]$ $\approx n_{\rm p}(0) \exp\left[e(V_{\rm b-i}-V_{\rm d})/(kT)\right]$ where $V_{\rm d}$ is the applied bias
- -> diffusion currents in depletion region:

$$j_{\text{n}\mid_{x=0}} = eD_{\text{n}} \partial n_{\text{p}}/\partial x_{\mid_{x=0}} = eD_{\text{n}} n_{\text{p}}(0)/L_{\text{n}} [\exp(eV_{\text{d}}/(kT)-1]]$$

 $j_{\text{p}\mid_{x=0}} = -eD_{\text{p}} \partial p_{\text{n}}/\partial x_{\mid_{x=0}} = eD_{\text{p}} p_{\text{n}}(0)/L_{\text{p}} [\exp(eV_{\text{d}}/(kT)-1]]$

-> total diode current through area A is $I_d = A(j_n + j_p)$, hence $I_d = I_S$ [exp $(eV_d/(kT) - 1]$ where $I_S = eA[D_p p_n(0)/L_p + D_n n_p(0)/L_n]$]





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types of diodes and applications

- rectifying diode: blocks for V<V_{b-i} and conducts for V>V_{b-i}
- biasing diode: yields voltage drop of V_{b-1} (~0.6V for silicon)
- LEDs: light-emitting diodes when a direct band-gap semiconductor pn-junction is forward biased with eV>E_g so electrons and holes are injected from opposite ends and recombine near the contact area, creating photons (light)
- Zener diodes: reverse biased, yield constant voltage drop independent of current flow
- APDs: avalanche photodiodes are operated under very strong reverse bias (so normally only leakage current); if a high-energy photon or X-ray strikes, it produces e-h pairs that can be separated in the field and due to their high energy produce an avalanche of further charge carriers (-> high current pulse)

